



APMP 2011

# SYMPOSIUM ON NANOTECHNOLOGY AND MATERIAL METROLOGY

Measurement and Standards Challenges and Strategy for Nanotechnology

Dr. Kamal Hossain, NPL, UK

Measurements and Analysis of Nano Materials

Dr. Daisuke Fujita, NIMS, Japan

Development of the Thin Film CRM and SWCNT

Dr. Lingling Ren, NIM, China

Development of Nanoparticle Standards: Current Status and Future Needs

Dr. Kensei Ehara, NMIJ, Japan

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**14:00-16:30**

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Asia Pacific Metrology Programme (APMP)

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